24Gb DDR5 SDRAM Addendum

MT60B6G4, MT60B3G8, MT60B1536M16 Die Revision C

Features

This document describes the product specifications that are unique to Micron 24Gb DDR5 Die Revision C device. For general Micron DDR5 SDRAM specifications, see the Micron DDR5 SDRAM Core Product Data Sheet. Content in this 24Gb Die Revision C DDR5 SDRAM data sheet addendum supersedes content defined in the core data sheet.

- $V_{DD} = V_{DDO} = 1.1V (NOM)$
- V_{pp}= 1.8V (NOM)
- \bullet On-die, internal, adjustable V_{REF} generation for DQ, CA, CS
- 1.1V pseudo open-drain I/O
- T_C maximum up to 95°C
 - 32ms, 8192-cycle refresh up to 85°C
 - 16ms, 8192-cycle refresh at >85°C to 95°C
- 32 internal banks (x4, x8): 8 groups of 4 banks each
- 16 internal banks (x16): 4 groups of 4 banks each
- 16n-bit prefetch architecture
- 1 cycle/2 cycle command structure
- 2N mode
- All bank and same bank refresh
- Multi-purpose command (MPC)
- CS/CA training mode
- On-die ECC (bounded fault)
- · ECC transparency and error scrub
- Decision feedback equalization (DFE)

- · Loopback mode
- Command-based non-target (NT) nominal, DQ/DQS park, and dynamic WR on-die termination (ODT)
- sPPR and hPPR capability
- MBIST/mPPR capability
- · Per-DRAM addressability
- JEDEC JESD-79.5 compliant

Options ¹	Marking
 Configuration 	
– 6 Gig x 4	6G4
– 3 Gig x 8	3G8
– 1.5 Gig x 16	1536M16
• FBGA SDP Packages (Pb-free)	
– x4, x8 82-ball (9.5mm x 11mm)	JF
– x16 102-ball (9.5mm x 14mm)	HZ
• Timing – cycle time	
-0.312ns @ CL = 52	-64B
– 0.277ns @ CL = 58	-72B
-0.250ns @ CL = 64	-80B
 Operating temperature 	
– Commercial (0°C < T _C < 95°C)	None
• Die Revision	:C

Notes: 1. Not all options listed can be combined to define an offered product. Use the part catalog search on micron.com for available offerings.



Table 1: Part Numbers and Timing Parameters

Part Number	Configuration	Memory Clock/ Data Rate	Clock Cycles (CL- _n RCD- _n RP)	Designation ¹
MT60B6G4JF-64B:C	6Gb x4	0.312ns/6400 MT/s	52-52-52	Production
MT60B3G8JF-64B:C	3Gb x8	0.312ns/6400 MT/s	52-52-52	Production
MT60B1536M16HZ-64B:C	1.5Gb x16	0.312ns/6400 MT/s	52-52-52	Production
MT60B6G4JF-72B:C	6Gb x4	0.277ns/7200 MT/s	58-58-58	Preliminary
MT60B3G8JF-72B:C	3Gb x8	0.277ns/7200 MT/s	58-58-58	Preliminary
MT60B1536M16HZ-72B:C	1.5Gb x16	0.277ns/7200 MT/s	58-58-58	Preliminary
MT60B6G4JF-80B:C	6Gb x4	0.250ns/8000 MT/s	64-64-64	Advance
MT60B3G8JF-80B:C	3Gb x8	0.250ns/8000 MT/s	64-64-64	Advance
MT60B1536M16HZ-80B:C	1.5Gb x16	0.250ns/8000 MT/s	64-64-64	Advance

Notes: 1. **Production**: Although considered final, these specifications are subject to change as further product development and data characterization sometimes occur. **Preliminary**: For evaluation and reference purposes only and are subject to change by Micron without notice. Products are only warranted by Micron to meet Micron's production data sheet specifications.

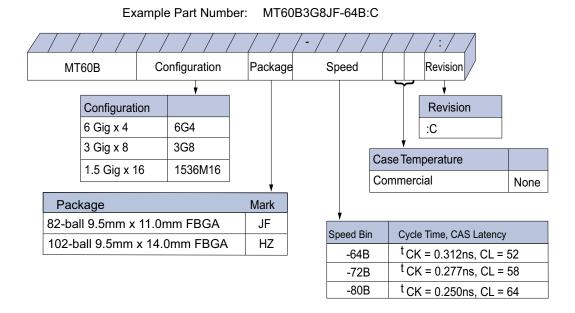
Table 2: 24Gb Addressing

Configuratio	n	6Gb x4	3Gb x8	1.5Gb x16
Bank address	Number of bank groups/number of banks per bank group/number of banks	8/4/32	8/4/32	4/4/16
	Bank group address	BG0-BG2	BG0-BG2	BG0-BG1
	Bank address in a bank group	BA0-BA1	BA0-BA1	BA0-BA1
Row address		R0-R16 ¹	R0-R16 ¹	R0-R15 ¹
Column addre	ss	C0-C10	C0-C9	C0-C9
Page size		1KB	1KB	2KB
Chip IDs/maxir	num stack height	CID0-3 / 16H	CID0-3 / 16H	CID0-3 / 16H

Notes: 1. For non-binary densities, a quarter of the row address space is invalid. When the MSB address bit is HIGH, the MSB-1 address must be LOW.



Figure 1: Order Part Number Example





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General Notes and Functional Block Diagrams

General Notes

- The functionality and the timing specifications discussed in this data sheet are for the DLL enable mode of operation (normal operation), unless specifically stated otherwise.
- Throughout the data sheet, the various figures and text refer to DQs as "DQ." The DQ term is to be interpreted as any and all DQ collectively, unless specifically stated otherwise.
- The terms "_t" and "_c" are used to represent the true and complement of a differential signal pair. These terms replace the previously used notation of "#" and/or over-bar characters. For example, differential data strobe pair DQS, DQS# is now referred to as DQS_t, DQS_c.
- The term "_n" is used to represent a signal that is active LOW and replaces the previously used "#" and/or overbar characters. For example: CS# is now referred to as CS n.
- The terms "DQS" and "CK" found throughout the data sheet are to be interpreted as DQS_t, DQS_c and CK_t, CK_c respectively, unless specifically stated otherwise.
- Complete functionality may be described throughout the entire document; any page or diagram may have been simplified to convey a topic and may not be inclusive of all requirements.
- Any specific requirement takes precedence over a general statement.
- Any functionality not specifically stated here within is considered undefined, illegal, and not supported, and can result in unknown operation.
- Addressing is denoted as BG[n] for bank group, BA[n] for bank address, and A[n] for row/col address.
- A NOP is considered a valid command for very specific states such as power-down exit, self-refresh exit, and reset. The NOP must satisfy any associated command timings with respect to the preceding valid command.
- Not all features described within this document may be available on the Rev. A (first) version.
- Not all specifications listed are finalized industry standards; best conservative estimates have been provided when an industry standard has not been finalized.
- Although it is implied throughout the specification, the DRAM must be used after reaching a stable power-on level, which is achieved by following the proper voltage ramp and power-up initialization sequence procedures as outline in this specification.
- Not all features designated in the data sheet may be supported by earlier die revisions due to late definition by JEDEC.

Definitions of the Device-Pin Signal Level

- HIGH: A device pin is driving the logic 1 state.
- LOW: A device pin is driving the logic 0 state.
- High-Z or (HI-Z/Hi-Z): A device pin is tri-state
- ODT: A device pin terminates with the ODT settings, which could be terminating or tri-state depending on the mode register settings.

Definitions of the Bus Signal Level

- HIGH: One device on the bus is HIGH, and all other devices on the bus are either ODT or High-Z. The voltage level on the bus is nominally $V_{\rm DDO}$.
- LOW: One device on the bus is LOW, and all other devices on the bus are either ODT or High-Z. The voltage level on the bus is nominally V_{OL(DC)} if ODT was enabled, or V_{SSO} if High-Z.
- High-Z or (HI-Z/Hi-Z): All devices on the bus are High-Z. The voltage level on the bus is undefined as the bus is floating.



- \bullet ODT: At least one device on the bus is ODT, and all others are High-Z. The voltage level on the bus is nominally V_{DDO} .
- The specification requires 8,192 refresh commands within 32ms between 0° C and 85° C. This allows for a t REFI of 3.9 μ s in normal refresh mode. The specification also requires 8,192 refresh commands within 16ms between 85° C and 95° C. This allows for a t REFI of 1.95 μ s in normal refresh mode.

Industrial Temperature

An industrial temperature (IT) device option requires that the case temperature not exceed below -40°C or above 95°C. JEDEC specifications require the refresh rate to double when T_{C} exceeds 85°C; this also requires use of the high-temperature self-refresh option. Additionally, ODT resistance and the input/output impedance must be derated when operating outside of the commercial temperature range, when T_{C} is between -40°C and 0°C .

Automotive Temperature

The automotive temperature (AT) device option requires that the case temperature not exceed below -40°C or above 105°C . The specifications require the refresh rate to 2X when T_{C} exceeds 85°C ; 4X when T_{C} exceeds 95°C . Additionally, ODT resistance and the input/output impedance must be derated when operating temperature $T_{\text{C}} < 0^{\circ}\text{C}$.



Figure 2: 6 Gig x4 Functional Block Diagram

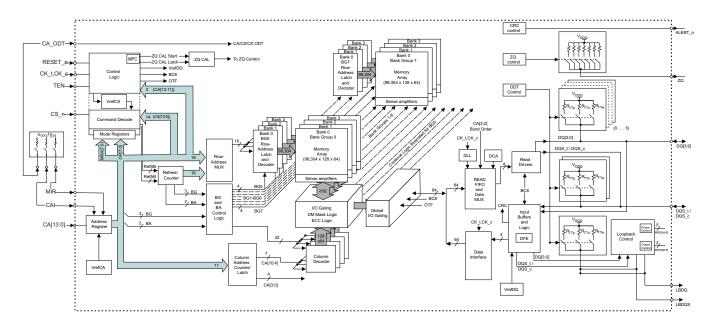


Figure 3: 3 Gig x8 Functional Block Diagram

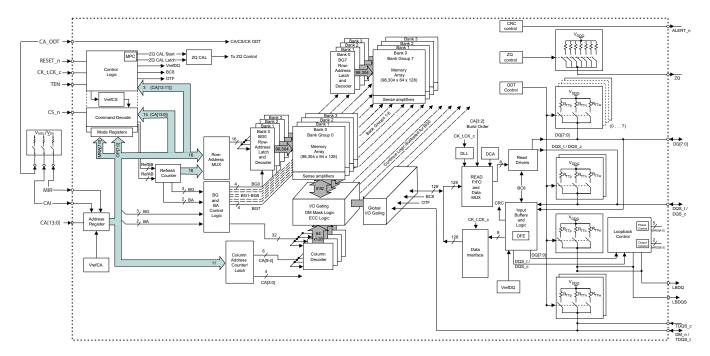
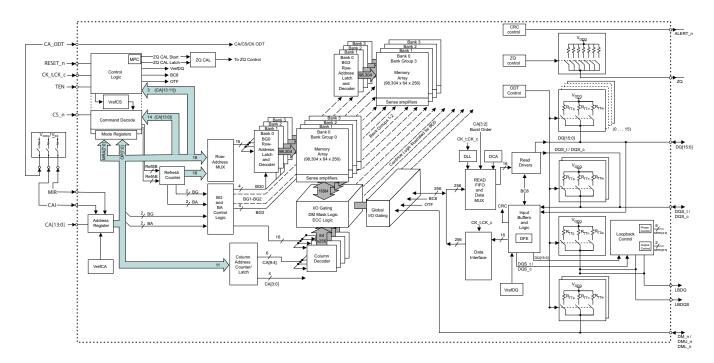




Figure 4: 1.5 Gig x16 Functional Block Diagram





DDR5 Function Matrix

DDR5 SDRAM has several features supported by configuration width, by density, by speed and by device die Rev. The following table is the summary of the features supported by 24Gb Die Revision B by configuration width. The functional matrix will be defined in each device-specific data sheet; therefore, device, speed and density options will vary by device data sheet.

Table 3: DDR5 Function Matrix - 24Gb Die Rev. C. V: Supported, Blank: Not Supported

Function	х4	х8	x16	MR Default State	Notes
JEDEC Mandatory					
BC8 OTF	V	V	V		
TDQS		V			
Data Mask (DM)		V	V		
Data Output Disable	V	V	V		
Connectivity Test Mode (CT)	V	V	V		
CA/CS/CK ODT	V	V	V		
2N Mode	V	V	V		
Per DRAM Addressability (Enum)	V	V	V		
Mode Register Read (MRR)	V	V	V		
Mode Register Write (MRW)	V	V	V		
Multi-Purpose Command (MPC)	V	V	V		
ZQ calibration	V	V	V		
CA Vref Training	V	V	V		
CS Vref Training	V	V	V		
DQ Vref Training	V	V	V		
CS Training Mode (CSTM)	V	V	V		
CA Training Mode (CATM)	V	V	V		
Write Leveling Training	V	V	V		
DQS Interval Oscillator	V	V	V		
Read Training Pattern Mode (LFSR)	V	V	V		
Write Pattern Command	V	V	V		
Duty Cycle Adjuster (DCA) I	V	V	V	MR42:OP[1:0] = 10(R)	1
Loopback Mode	V	V	V		
Decision Feedback Equalization (DFE)	V	V	V		
WRITE CRC	V	V	V		
READ CRC	V	V	V		
Programmable Preamble	V	V	V		
Programmable Postamble	V	V	V		
sPPR	V	V	V		
hPPR	V	V	V		
PPR using DQ[3:0] only					



Table 3: DDR5 Function Matrix - 24Gb Die Rev. C. V: Supported, Blank: Not Supported (Continued)

Function	х4	x8	x16	MR Default State	Notes
On-Die-ECC	V	V	V		
ECC Transparency and Error Scrub	V	V	V		
				MR58:OP[0] = 0 (R)	2
Defeate Management (DEMA)				MR58:OP[7:5] = 110 (R)	
Refresh Management (RFM)	V	V	V	MR58:OP[4:1] = 1010 (R)	3
				MR59:OP[7:6] = 00 (R)	
Fine Granularity Refresh (FGR)	V	V	V		
Same Bank Refresh	V	V	V		
Same Bank Precharge	V	V	V		
Maximum power saving mode (MPSM)	V	V	V		
CS Geardown(>= 7200 MT/s)	V	V	V		
JEDEC Optional			1		
MR65-MR69 Serial Number				MR65 - MR69 = 0x00 (R)	
BL32					
BL32 OTF					
WICA 1/2 step	V	V	V		
Duty Cycle Adjuster (DCA) II	V	V	V	MR42:OP[7] = 1(SR)	
MBIST/mPPR	V	V	V	MR23:OP[4] = 1 (SR)	
sPPR undo/lock	V	V	V	MR23:OP[2] = 1 (SR)	
Adaptive RFM	V	V	V		
Discarded DEM	1/	.,	M	MR59:OP[0] = 1 (SR)	_
Directed RFM	V	V	V	MR59:OP[3] = 0 (R)	5
Package output driver test mode (PODTM)				MR5:OP[3] = 0 (R)	
Partial array self refresh (PASR)	V	V	V	MR19:OP[7] = 1 (R)	
Refresh interval rate (RIR)	V	V	V	MR4:OP[3] = 1 (SR)	
Rx CTLE (CS_n, CA, DQS)	V	V	V	M22:OP[3] = 1 (R)	
MR4 wide range refresh rate support	V	V	V	MR4:OP[5] = 1 (R)	
Test Mode MR (MR9)					6
ECS Writeback Suppression	V	V	V		
x4 RMW Suppression	V				
Clk Sync on SR Exit by first NOP (≥6800 MT/s, with fuse option)	V	V	V	MR13:OP[5] = 1 (SR)	

Notes: 1. Device supports DCA for four-phase internal clock(s).

- 2. RFM not required.
- 3. RAAMMT, RAAIMT, and RAA counter decrement are only applicable if the RFM requirement bit is set to 1 (MR58:OP[0]=1) or ARFM is set to level A, B, or C.
- 4. Data rates of >=7200 MT/s are not supported on this die revision.
- 5. BRC support level (MR59:OP[3]) is only applicable if DRFM Enable status read bit is set to 1 (MR59:OP[0]=1)
- 6. Test Mode (TM) is a vendor-specific mode register; not used by Micron.



DDR5 Package Pinout and Assignments

Rows

The x4/x8 device has 13 electrical rows of balls. The x16 device has 17 electrical rows of balls. Electrical is defined as rows that contain signal ball or power/ground balls. Additional rows of inactive balls may be available for mechanical support.

Ball Pitch

The device uses a ball pitch of 0.8mm x 0.8mm.

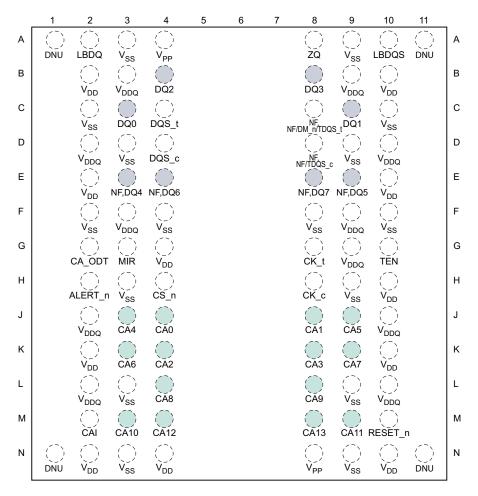
Columns

The number of depopulated columns is 3.

The device has six electrical columns of balls in two sets of three columns. Between the electrical columns are three columns where no balls are populated. Electrical is defined as columns that contain signal ball or power/ground balls. Additional columns of inactive balls may be available for mechanical support.



Figure 5: x4/x8 Ballout Using MO-210-AN - 82-Ball



Notes: 1. DQ4-DQ7 higher-order DQ pins are connected but not used in the x4 configuration.

- 2. DM, TDQS_t and TDQS_c are not valid for the x4 configuration.
- 3. A comma "," separates the configuration. A slash "/" defines a mode register-selectable function, command/address function, density or package dependence.



Figure 6: x16 Ballout Using MO-210-AT -102 Ball

	1	2	3	4	5	6	7	8	9	
Α	LBDQ	V _{SS}	() V _{PP}				() ZQ	V _{ss}	LBDQS	Α
В	$\binom{\bigcirc}{V_{DD}}$	V _{SS}	DQU2				DQU3	V _{SS}	$(\widehat{})$	В
С	/~~		·				DMU_n	V _{DDQ} DQU1	V _{DD}	С
D	$\bigcirc v_{S} s (\bigcirc) v_{D} (\bigcirc) v_{D} (\bigcirc) v_{S} (\bigcirc) v_{S} (\bigcirc) v_{D} (\bigcirc) v_$						RFU	V _{SS}	()	D
E	V _{DDQ}	V _{ss}	DQSU_c				RFU	V _{SS} DQU5		E
F	V _{DD}	DQU4	DQU6				DQU7	DQU5	V _{DD}	F
(V _{DD}	V _{DDQ}	DQL2				DQL3	V _{DDQ} DQL1	V _{DD}	
G	V _{SS}	DQL0	DQSL_t				DML_n	DQL1	V _{SS}	G
Н	V _{DDQ}	\hat{V}_{SS}	DQSL_c				() RFU	() V _{ss}	v _{DDQ}	Н
J	() V _{DD}	DQL4	DQL6				DQL7	DQL5	$\stackrel{\bigcirc}{V_{DD}}$	J
K	V _{DD}	(_) V _{DDO}	() V _{SS}				() V _{ee}	(_) V _{DDO}	() V ₉₉	K
L	() CA_ODT	V _{SS} DQL4 V _{DDQ} MIR	V _{DD}				() CK t	Vone	V _{DD} () V _{SS} () TEN	L
М	ALEDT n		()					DQL5 VDDQ VDDQ VSS CA5 CA7	V _{DD}	М
N	() V _{DDQ}	CA4	CA0				CA1	CA5	V _{DDQ}	N
Р	() V _{DD}	CA6	CA2				CA3	CA7	V _{DD}	Р
R	V_{DDQ}	() V _{SS}	CA8				CA9	V _{SS}	V _{DDQ}	R
Т	() ČÁI	() CA10	CA12				CA13	CA11	() REŠĒT_n	Т
U	V _{DDQ} O _{DD} O _{CAI} O _{DD}	() V _{ss}	() V _{DD}				CA9 CA13 CA13	() V _{SS}	() V _{DD}	U



Table 4: Pinout Description

Symbol	Туре	Function
CK_t, CK_c	Input	Clock: CK_t and CK_c are differential clock inputs. All command/address and control input signals are sampled on the crossing of the positive edge of CK_t and negative edge of CK_c.
CS_n	Input	Chip Select: All commands are masked when CS_n is registered HIGH. CS_n provides for external rank selection on systems with multiple ranks. CS_n is considered part of the command code and is used to enter and exit the parts from power down mode and self refresh mode. While not in self refresh mode, the CS_n input buffer operates with the same ODT and V_{REF} parameters as configured by the CA_ODT strap setting or mode register. When in self refresh mode, the CS_n is a CMOS rail-to-rail signal with DC HIGH and LOW at 80% and 20% of V_{DDQ} .
DM_n, DMU_n, DML_n	Input	Input Data Mask: DM_n is an input mask signal for write data. Input data is masked when DM_n is sampled LOW coincident with that input data during a write access. DM_n is sampled on both edges of DQS. DM_n is not supported on x4 devices. For x8 devices, the function of DM_n is enabled by the mode register. For x16 devices, the function of DMU_n/DML_n is enabled by the mode register.
CA[13:0]	Input	Command/Address Inputs: Command/Address (CA) signals provide the command and address inputs according to the Command Truth Table. Because some commands are multicycle, the pins may not be interchanged between devices on the same bus.
RESET_n	Input	Active Low Asynchronous Reset: Reset is active when RESET_n is LOW, and inactive when RESET_n is HIGH. RESET_n must be HIGH during normal operation. RESET_n is a CMOS rail-to-rail signal with DC HIGH and LOW at 80% and 20% of V _{DDQ} .
DQ	Input/Output	Data Input/Output: Bidirectional data bus. If CRC is enabled via the mode register, CRC code is added at the end of a data burst.
DQS_t, DQS_c, DQSU_t, DQSU_c, DQSL_t, DQSL_c	Input/Output	Data Strobe: Output with read data, input with write data, edge-aligned with read data, centered in write data. For x16 devices, DQSL corresponds to the data on DQL0-DQL7; DQSU corresponds to the data on DQU0-DQU7. The data strobes DQS_t, DQSL_t and DQSU_t are paired with differential signals DQS_c, DQSL_c, and DQSU_c, respectively, to provide differential pair signaling to the system during reads and writes. The device supports differential data strobe only, not single-ended.
TDQS_t, TDQS_c	Output	Termination Data Strobe: Applicable to x8 devices only. When enabled via the mode register, the device enables the same termination resistance function on TDQS_t/TDQS_c that is applied to DQS_t/DQS_c. When disabled via the mode register, DM/TDQS provides the data mask function depending on the MR setting; TDQS_c is not used. x4/x16 devices must disable the TDQS function via the mode register.
ALERT_n	Input/Output	Alert: If there is an error in CRC, ALERT_n drives LOW for the period time interval and returns HIGH. During the connectivity test mode, this pin functions as an input. Usage of this signal is system-dependent. In cases where this pin is not connected, ALERT_n must be bonded to V _{DDQ} on the system board.
TEN	Input	Connectivity Test Mode Enable: A HIGH on this pin enables CONNECTIVITY TEST MODE operation along with other pins. It is a CMOS rail-to-rail signal with AC HIGH and LOW at 80% and 20% of V_{DDQ} . Usage of this signal is system-dependent. This pin is pulled LOW internally with a weak pulldown resistor to V_{SS} .



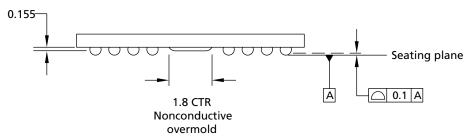
Table 4: Pinout Description (Continued)

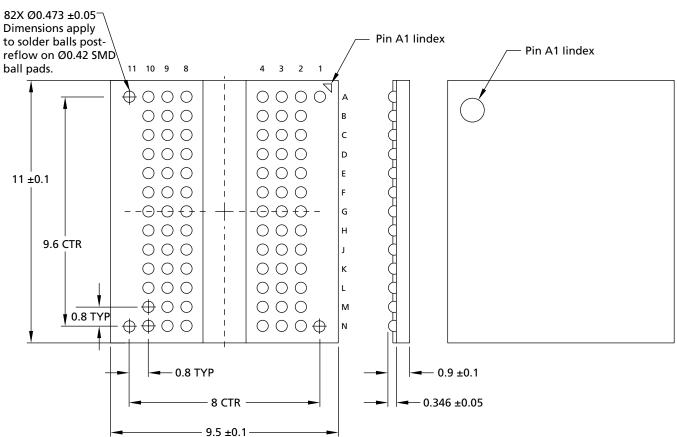
Symbol	Туре	Function
MIR	Input	Mirror: Used to inform the system that this device is being run in mirrored mode instead of standard mode. With the MIR pin connected (strapped) to V _{DDQ} , the device internally swaps even-numbered CA with the next higher odd-number CA. The MIR pin must be tied to V _{SS} if no CA mirror is required. Mirror pair examples: CA2 with CA3 (not CA1) CA4 with CA5 (not CA3). Note: the CA[13] function is only relevant for certain densities (including stacking). In the case that CA[13] is not used, its ball location, considering whether MIR is used or not, should be connected (strapped) to V _{DDQ} . No active signaling requirements required.
CAI	Input	Command and Address Inversion: With this pin connected (strapped) to V_{DDQ} , the device internally inverts the logic level present on all CA signals. The CAI pin must be connected to V_{SS} if no CA inversion is required. No active signaling requirements required.
CA_ODT	Input	ODT for Command and Address: Apply Group A settings if the pin is connected (strapped) to V_{SS} ; apply Group B settings if the pin is connected (strapped) to V_{DDQ} . See the mode register defaults table for details. No active signaling requirements required.
LBDQ	Output	Loopback Data Output: The output of this device on the Loopback Output Select defined in MR53:OP[4:0]. When loopback is enabled, it is in driver mode using the default RON described in the Loopback Function section. When loopback is disabled, the pin is either terminated or High-Z based on MR36:OP[2:0].
LBDQS	Output	Loopback Data Strobe Output: A single-ended strobe with the rising edged aligned with loopback data edge, falling edge aligned with data center. When loopback is enabled, it is in driver mode using the default RON described in the Loopback function section. When loopback is disabled, the pin is either terminated or High-Z based on MR36:OP[2:0].
RFU	Input/Output	Reserved for future use.
DNU		Do not use.
NF		No function: Internal connection is present but has no function.
V_{DDQ}	Supply	DQ power supply; 1.1V nominal.
V _{DD}	Supply	Power supply; 1.1V nominal.
V _{SS}	Supply	Ground
V _{PP}	Supply	Activating power supply; 1.8V nominal.
ZQ	Reference	Reference pin for ZQ calibration. This ball is tied to an external 240 ohm resistor (RZQ), which is tied to V_{SS} .



Package Dimensions

Figure 7: 82-Ball VFBGA - MO-210-AN (x4/x8)



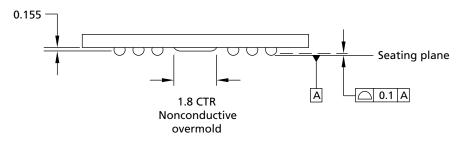


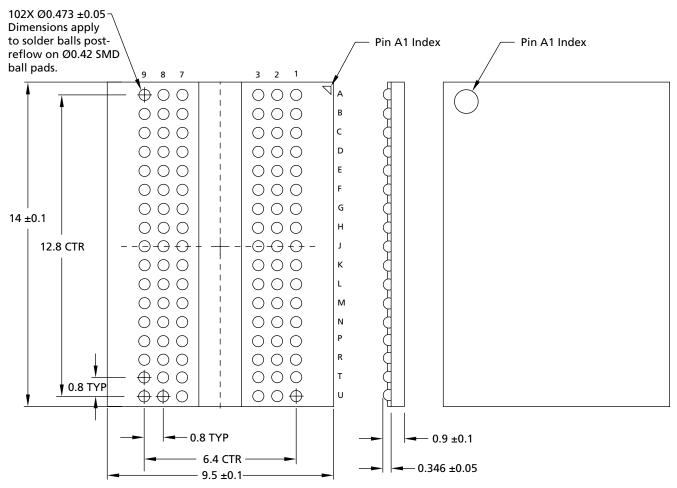
Notes: 1. All dimensions are in millimeters.

2. Solder ball material: SACQ (92.45% Sn, 4% Ag, 3% Bi, 0.5% Cu, 0.05% Ni).



Figure 8: 102-Ball VFBGA - MO-210-AT (x16)





Notes: 1. All dimensions are in millimeters.

2. Solder ball material: SACQ (92.45% Sn, 4% Ag, 3% Bi, 0.5% Cu, 0.05% Ni).

Table 5: Package Thermal Resistance Characteristics

Die Revision	Package	Parameter	Value	Unit	Symbol
Rev C	82-ball "JF"	Junction-to-case (TOP)	3.6	°C/W	ΘΙC
		Junction-to-board	15.7	°C/W	ΘЈВ
	102-ball "HZ"	Junction-to-case (TOP)	3.6	°C/W	ΘЈС
		Junction-to-board	15.5	°C/W	ΘЈВ



DDR5 IDD,IPP,IDDQ Current Limits

DDR5 SDRAM current limits are measured and categorized based on the definitions found in the DDR5 Product Core data sheet. Refer to the IDD and IDDQ specification parameters and test conditions for details related to each current limit. Maximum values for $I_{\rm DD}$ currents considering worst-case conditions of process, temperature, and voltage.

Table 6: DDR5 IDD, IPP, IDDQ Current Limits - 24Gb Die Revision C

Parameter	Width	DDR5-6400	DDR5-7200	DDR5-8000	Unit	Notes
	x4	54	TBD	TBD		
IDD0	x8	54	TBD	TBD	mA	
	x16	66	TBD	TBD		
	х4	9	TBD	TBD		
IPP0	х8	9	TBD	TBD	mA	
	x16	10	TBD	TBD		
	х4	89	TBD	TBD		
IDDQ0	x8	91	TBD	TBD	mA	
	x16	96	TBD	TBD		
	x4	85	TBD	TBD		
IDD0F	x8	85	TBD	TBD	mA	
	x16	123	TBD	TBD	1	
	x4	11	TBD	TBD		
IPP0F	x8	11	TBD	TBD	mA	
	x16	14	TBD	TBD		
	x4	91	TBD	TBD		
IDDQ0F	x8	91	TBD	TBD	mA	
	x16	96	TBD	TBD		
	x4	47	TBD	TBD		
IDD2N	x8	47	TBD	TBD	mA	
	x16	47	TBD	TBD		
	x4	8	TBD	TBD		
IPP2N	x8	8	TBD	TBD	mA	
	x16	8	TBD	TBD		
	x4	94	TBD	TBD		
IDDQ2N	x8	94	TBD	TBD	mA	
	x16	94	TBD	TBD		
	x4	79	TBD	TBD		
IDD2NT	x8	79	TBD	TBD	mA	
	x16	79	TBD	TBD		



Table 6: DDR5 IDD, IPP, IDDQ Current Limits - 24Gb Die Revision C

Parameter	Width	DDR5-6400	DDR5-7200	DDR5-8000	Unit	Notes
	x4	8	TBD	TBD		
IPP2NT	x8	8	TBD	TBD	mA	
	x16	8	TBD	TBD		
	x4	96	TBD	TBD		
IDDQ2NT	х8	96	TBD	TBD	mA	
	x16	96	TBD	TBD		
	x4	43	TBD	TBD		
IDD2P	х8	43	TBD	TBD	mA	
	x16	43	TBD	TBD		
	x4	8	TBD	TBD		
IPP2P	х8	8	TBD	TBD	mA	
	x16	8	TBD	TBD		
	x4	73	TBD	TBD		
IDDQ2P	x8	73	TBD	TBD	mA	
	x16	73	TBD	TBD	1	
	x4	90	TBD	TBD	mA	
IDD3N	x8	90	TBD	TBD		
	x16	95	TBD	TBD		
	x4	8	TBD	TBD		
IPP3N	x8	8	TBD	TBD	mA	
	x16	8	TBD	TBD		
	x4	91	TBD	TBD		
IDDQ3N	x8	91	TBD	TBD	mA	
	x16	96	TBD	TBD		
	x4	89	TBD	TBD		
IDD3P	x8	89	TBD	TBD	mA	
	x16	92	TBD	TBD		
	x4	8	TBD	TBD		
IPP3P	x8	8	TBD	TBD	mA	
	x16	8	TBD	TBD		
	x4	69	TBD	TBD		
IDDQ3P	x8	69	TBD	TBD	mA	
	x16	71	TBD	TBD		
	x4	248	TBD	TBD	mA	
IDD4R	х8	290	TBD	TBD		
	x16	447	TBD	TBD	7	



Table 6: DDR5 IDD, IPP, IDDQ Current Limits - 24Gb Die Revision C

Parameter	Width	DDR5-6400	DDR5-7200	DDR5-8000	Unit	Notes
	x4	10	TBD	TBD		
IPP4R	х8	10	TBD	TBD	mA	
	x16	13	TBD	TBD		
	x4	228	TBD	TBD		
IDDQ4R	x8	318	TBD	TBD	mA	
	x16	609	TBD	TBD		
	x4	248	TBD	TBD		
IDD4RC	x8	287	TBD	TBD	mA	
	x16	437	TBD	TBD		
	x4	10	TBD	TBD		
IPP4RC	x8	10	TBD	TBD	mA	
	x16	13	TBD	TBD		
	х4	228	TBD	TBD		
IDDQ4RC	x8	316	TBD	TBD	mA	
	x16	607	TBD	TBD		
	x4	241	TBD	TBD	mA	
IDD4W	x8	292	TBD	TBD		
	x16	456	TBD	TBD		
	x4	22	TBD	TBD		
IPP4W	x8	22	TBD	TBD	mA	
	x16	39	TBD	TBD		
	x4	242	TBD	TBD		
IDDQ4W	x8	400	TBD	TBD	mA	
	x16	719	TBD	TBD		
	x4	235	TBD	TBD		
IDD4WC	x8	273	TBD	TBD	mA	
	x16	446	TBD	TBD		
	x4	22	TBD	TBD		
IPP4WC	x8	22	TBD	TBD	mA	
	x16	38	TBD	TBD		
	x4	241	TBD	TBD		
IDDQ4WC	х8	400	TBD	TBD	mA	
	x16	758	TBD	TBD		
	x4	353 TBD TBD				
IDD5B	х8	353	TBD	TBD	mA	
	x16	353	TBD	TBD	7	



Table 6: DDR5 IDD, IPP, IDDQ Current Limits - 24Gb Die Revision C

Parameter	Width	DDR5-6400	DDR5-7200	DDR5-8000	Unit	Notes
IPP5B	х4	35	TBD	TBD	mA	
	х8	35	TBD	TBD		
	x16	35	TBD	TBD		
IDDQ5B	x4	94	TBD	TBD	mA	
	х8	94	TBD	TBD		
	x16	94	TBD	TBD		
	x4	125	TBD	TBD	mA	
IDD5C	х8	125	TBD	TBD		
	x16	125	TBD	TBD		
	х4	15	TBD	TBD	mA	
IPP5C	х8	15	TBD	TBD		
	x16	15	TBD	TBD		
	х4	94	TBD	TBD	mA	
IDDQ5C	х8	94	TBD	TBD		
	x16	94	TBD	TBD		
	x4	332	TBD	396	mA	
IDD5F	х8	332	TBD	396		
	x16	332	TBD	TBD		
IPP5F	x4	33	TBD	TBD	mA	
	х8	33	TBD	TBD		
	x16	33	TBD	TBD		
IDDQ5F	x4	94	TBD	TBD	mA	
	x8	94	TBD	TBD		
	x16	94	TBD	TBD		
IDD6N(0-85C)	x4	172	TBD	TBD	mA	1
	х8	172	TBD	TBD		
	x16	172	TBD	TBD		
IPP6N (0-85C)	x4	20	TBD	TBD	mA	1
	x8	20	TBD	TBD		
	x16	20	TBD	TBD		
IDDQ6N (0-85C)	x4	67	TBD	TBD	mA	1
	x8	67	TBD	TBD		
	x16	67	TBD	TBD		
IDD6E (85-95C)	x4	258	TBD	TBD	mA	2
	x8	258	TBD	TBD		
	x16	258	TBD	TBD		



Table 6: DDR5 IDD, IPP, IDDQ Current Limits - 24Gb Die Revision C

Parameter	Width	DDR5-6400	DDR5-7200	DDR5-8000	Unit	Notes
IPP6E (85-95C)	x4	29	TBD	TBD	mA	2
	х8	29	TBD	TBD		
	x16	29	TBD	TBD		
IDDQ6E (85-95C)	х4	67	TBD	TBD	mA	2
	x8	67	TBD	TBD		
	x16	67	TBD	TBD		
IDD7	х4	396	TBD	TBD	mA	
	х8	447	TBD	TBD		
	x16	514	TBD	TBD		
	х4	24	TBD	TBD		
IPP7	x8	24	TBD	TBD	mA	
	x16	28	TBD	TBD		
IDDQ7	x4	221	TBD	TBD		
	x8	301	TBD	TBD	mA	
	x16	449	TBD	TBD		
IDD8	x4	38	TBD	TBD	mA	
	x8	38	TBD	TBD		
	x16	38	TBD	TBD		
IPP8	x4	7	TBD	TBD	mA	
	x8	7	TBD	TBD		
	x16	7	TBD	TBD		
IDDQ8	x4	67	TBD	TBD	mA	
	x8	67	TBD	TBD		
	x16	67	TBD	TBD		
IDD9	х4	173	TBD	TBD	mA	
	х8	173	TBD	TBD		
	x16	173	TBD	TBD		
IPP9	x4	22	TBD	TBD	mA	
	x8	22	TBD	TBD		
	x16	22	TBD	TBD		
IDDQ9	x4	204	TBD	TBD	mA	
	x8	204	TBD	TBD		
	x16	204	TBD	TBD		

Notes: 1. Applicable for MR4:OP[2:0]=001b, 010b.

2. Applicable for MR4:OP[2:0]=011b, 100b, 101b.



Revision History

Rev. B - 04/2025

• Corrected ball count for x4/x8, 82-ball VFBGA package

Rev. A - 01/2025

• Initial Release

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This data sheet contains minimum and maximum limits specified over the power supply and temperature range set forth herein.

Although considered final, these specifications are subject to change, as further product development and data characterization sometimes occur.